IEC 60749-41

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INTERNATIONAL STANDARD

NORME INTERNATIONALE

Semiconductor devices – Mechanical and climatic test methods – Part 41: Standard reliability testing methods of non-volatile memory devices

Dispositifs à semiconducteurs – Méthodes d'essais mécaniques et climatiques – Partie 41: Méthodes d'essai normalisées pour la fiabilité des dispositifs à mémoire non volatile

IEC 60749-41:2020-07(en-fr)

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